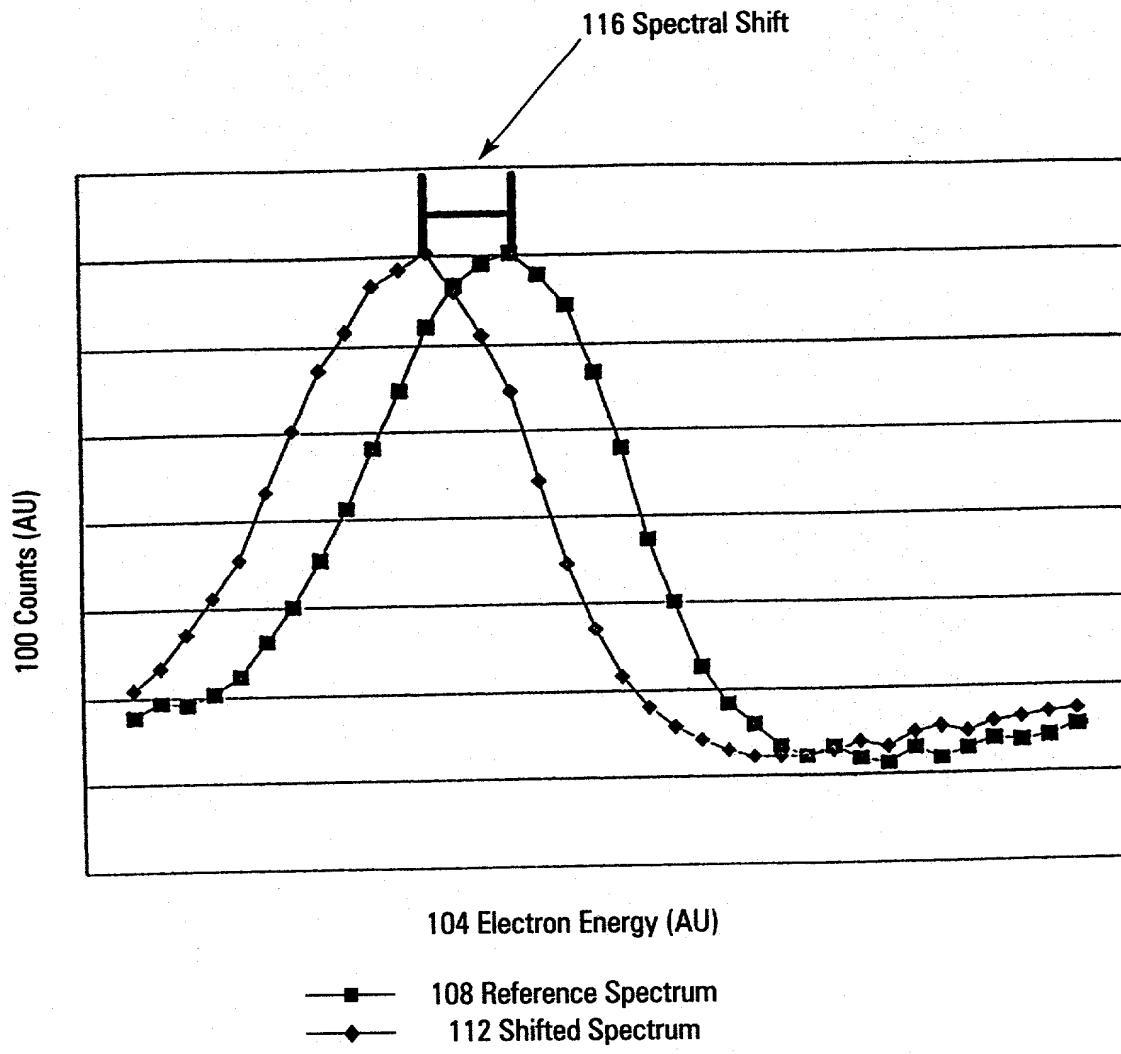


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*Fig. 1
(Prior Art)*

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Spectra for Depth Profile of Charging SiO_2 on Si
(Si KLL Auger Spectra)

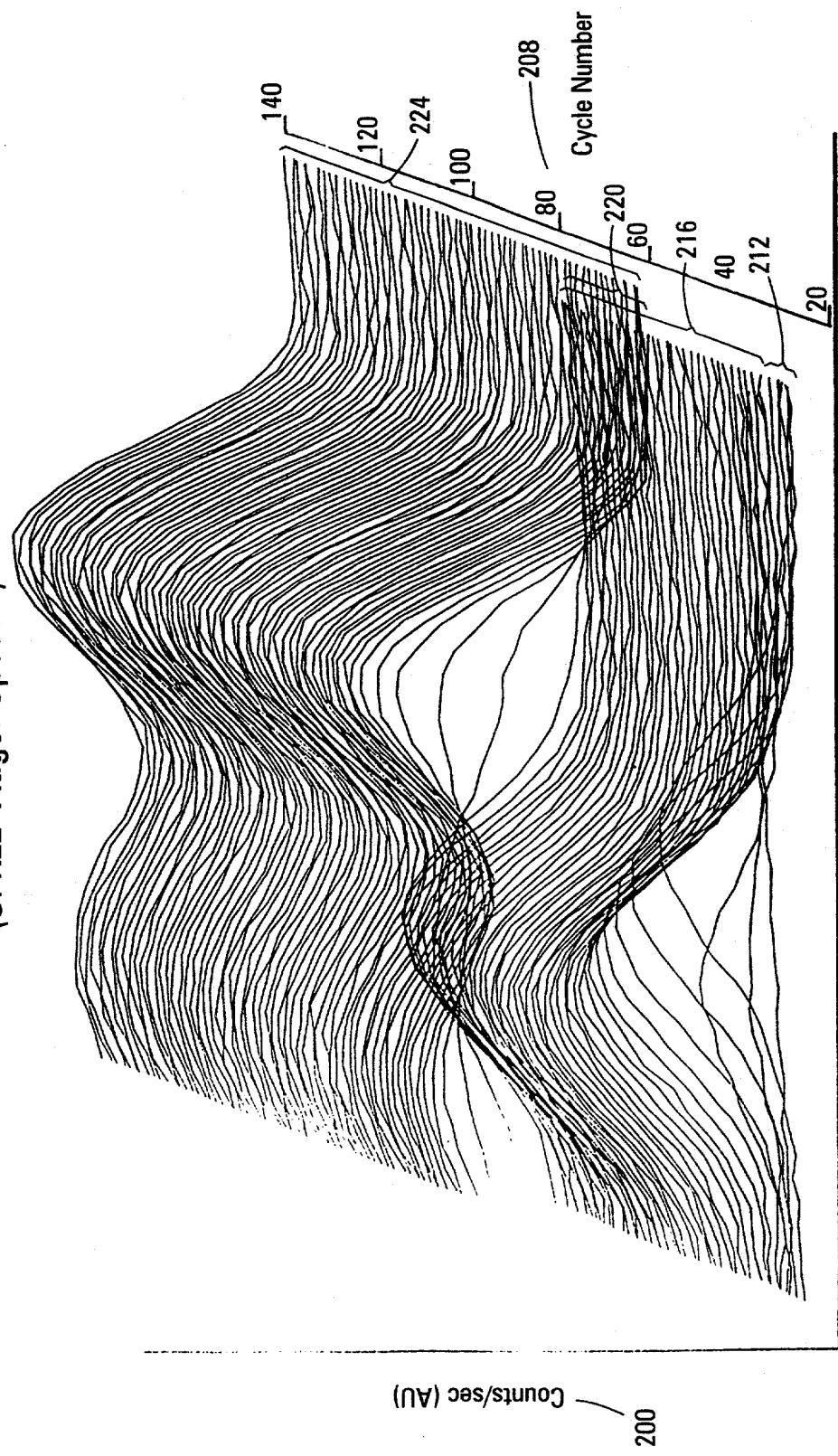


Fig. 2
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Profiles of Scaled Target-Factor Weighting Factors from Factor Analysis
of Uncompensated Auger Spectra from Charging SiO_2 on Si Substrate

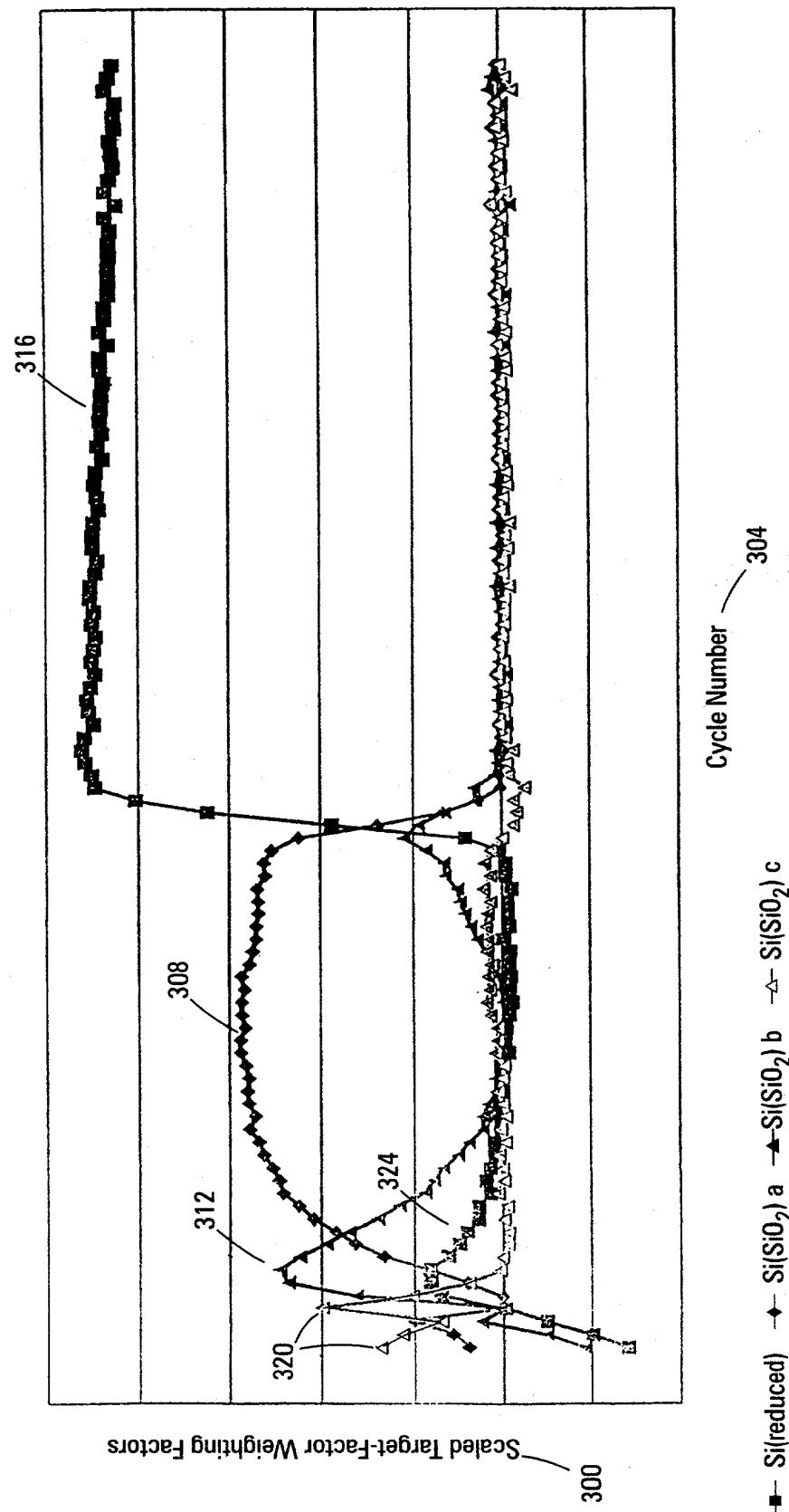
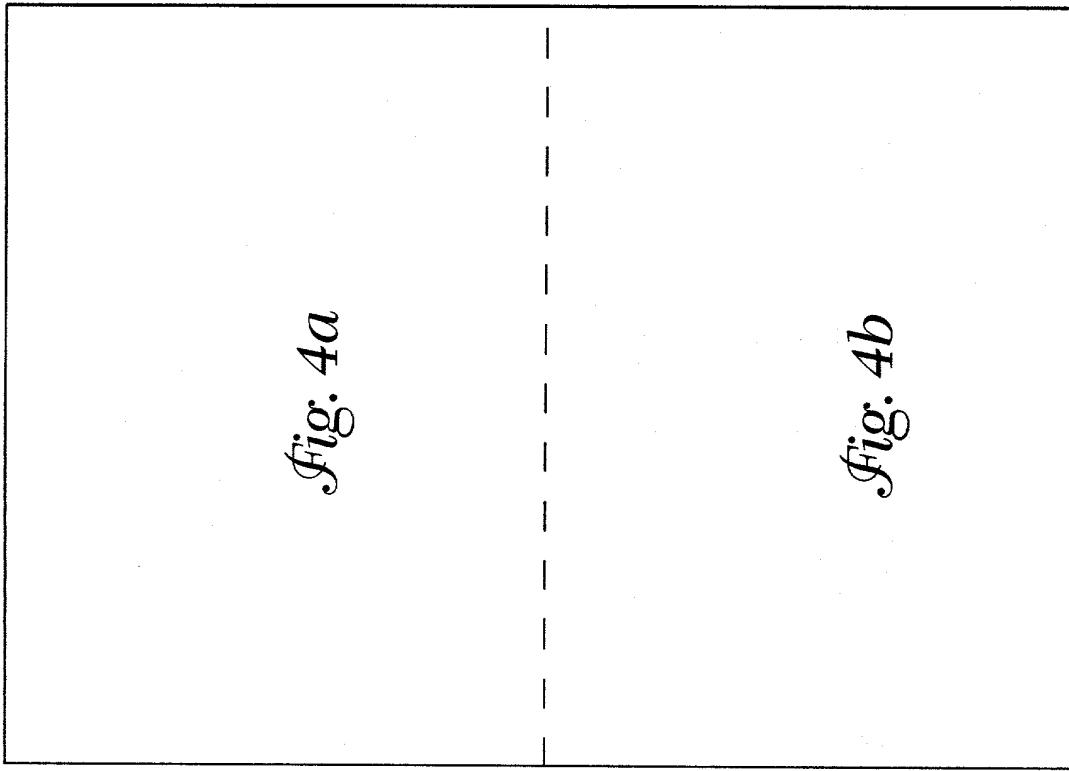


Fig. 3
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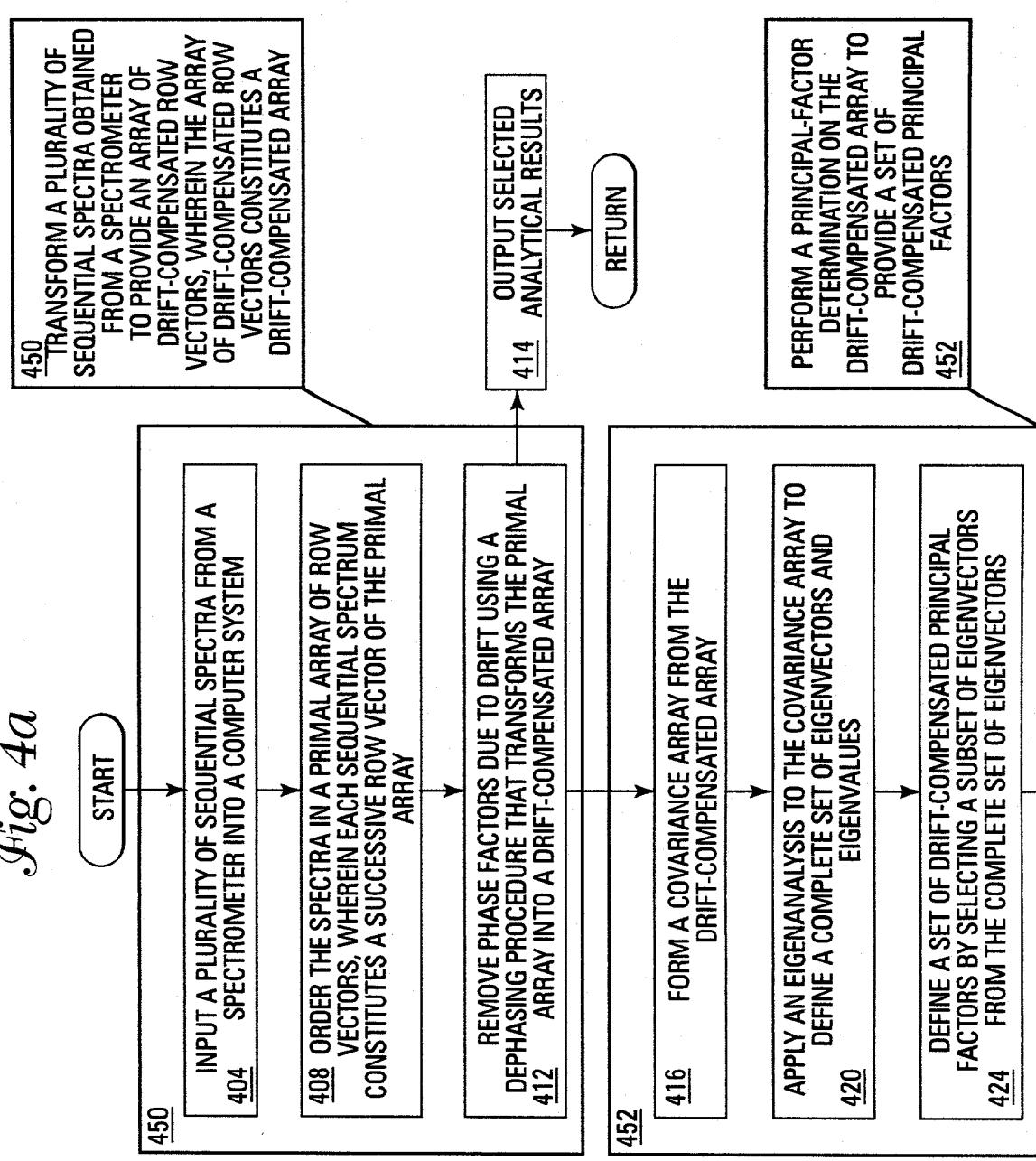
Fig. 4



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Fig. 4a

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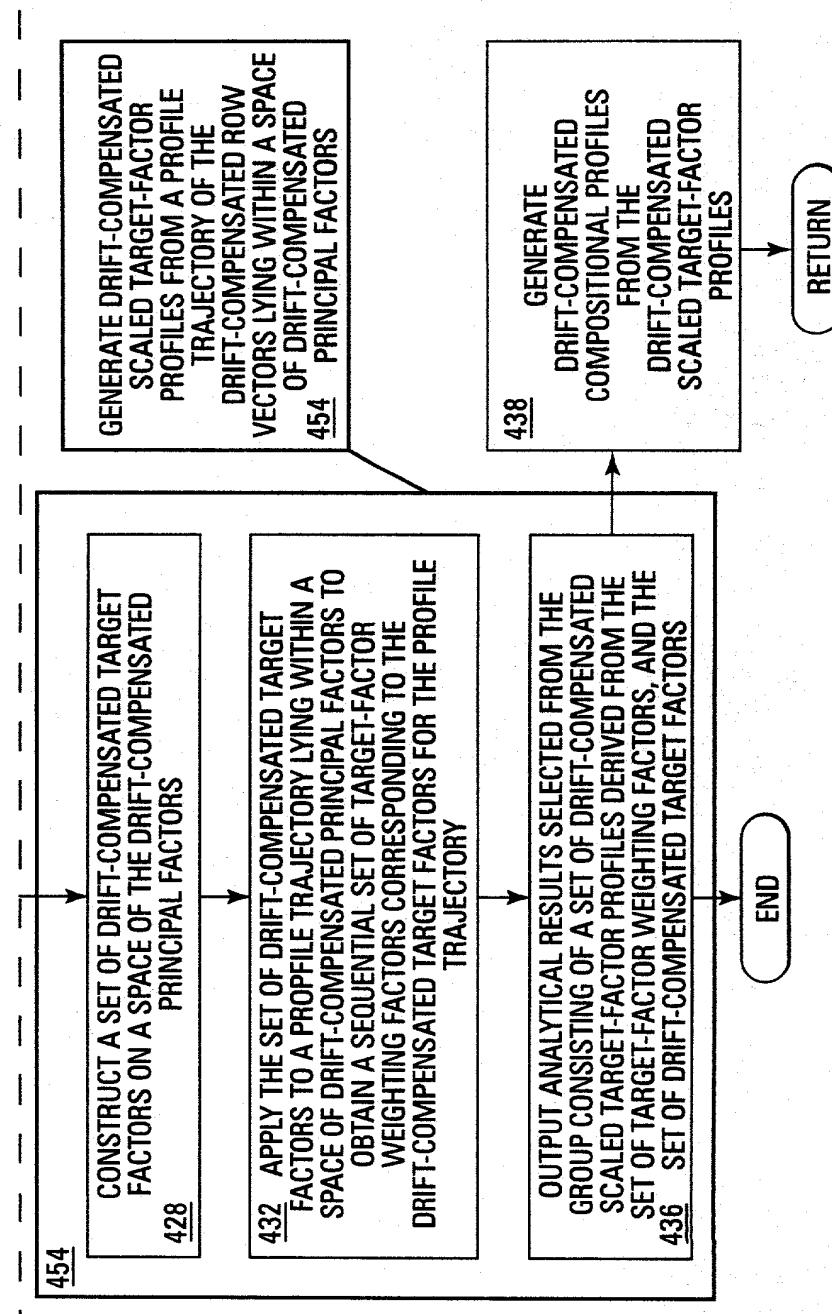
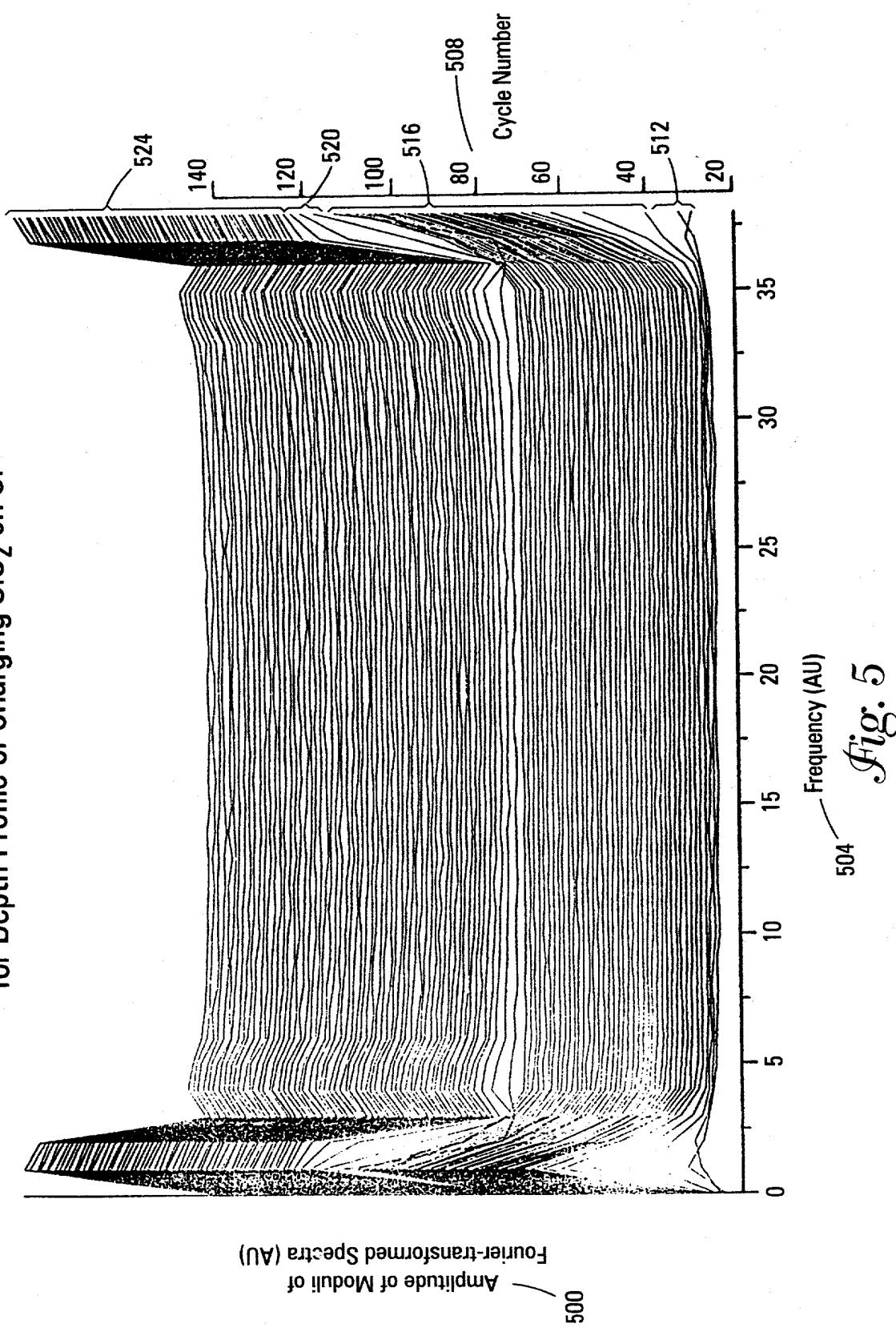


Fig. 4b

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Moduli of Fourier-transformed Spectra
for Depth Profile of Charging SiO_2 on Si



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Profiles of Scaled Target-Factor Weighting Factors from Factor Analysis of Moduli
of Fast-Fourier-Transformed Auger Spectra from Charging SiO_2 on Si Substrate

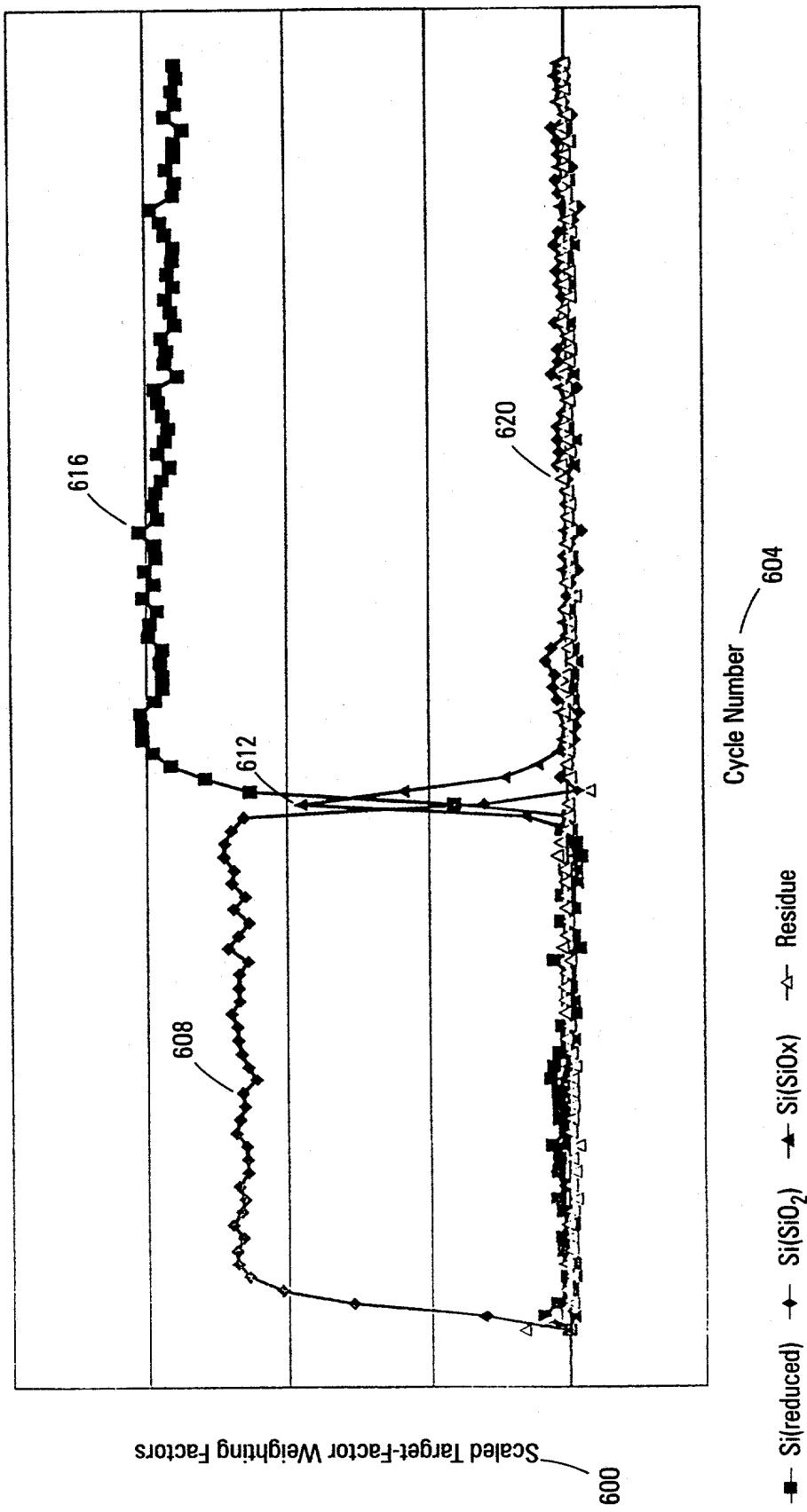


Fig. 6

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**Drift-Compensated Spectra Synthesized
from Selected Reference Spectra Fit to Primal Spectra
for Depth Profile of Charging SiO_2 on Si**

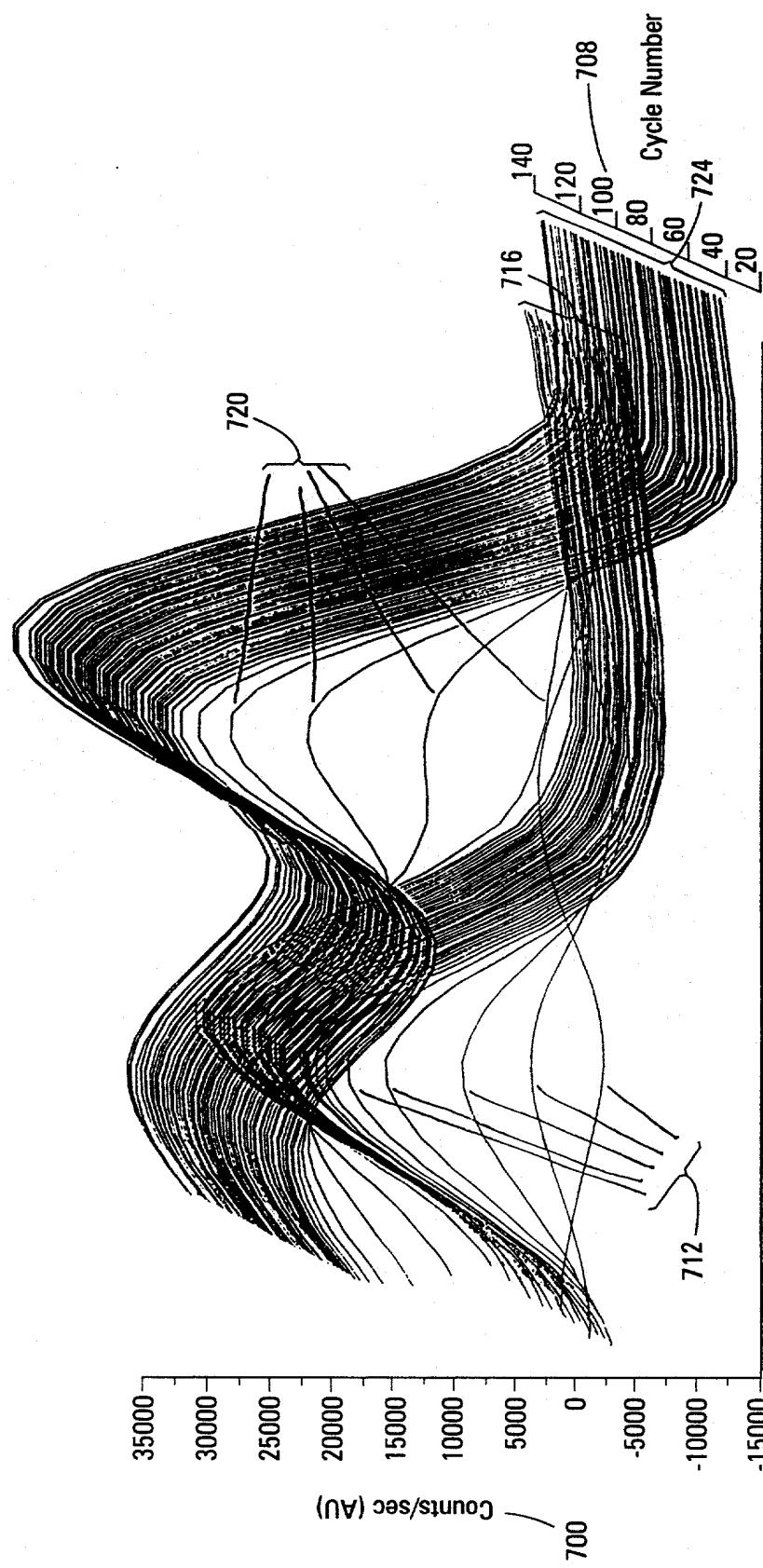
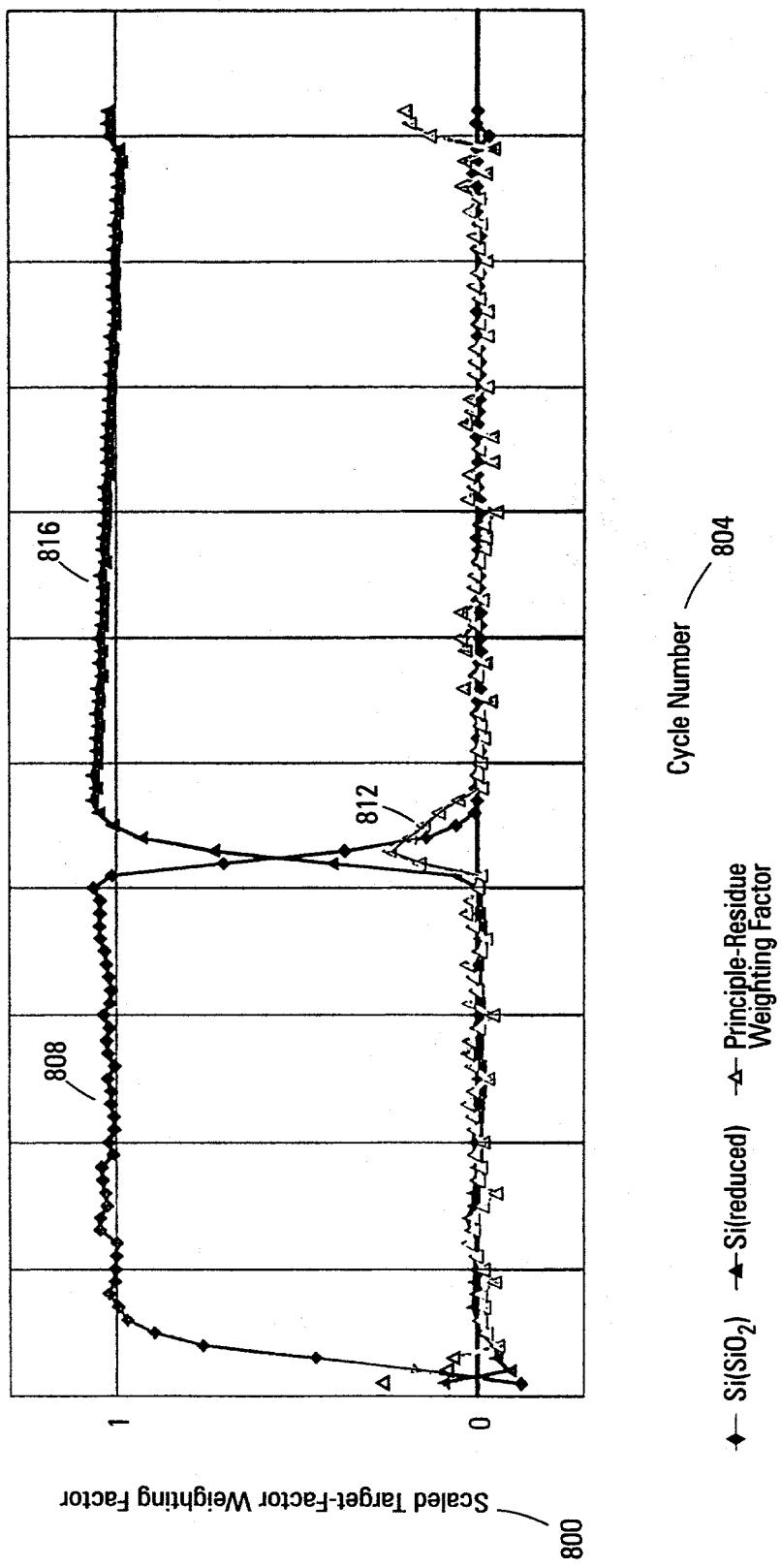


Fig. 7
704
712
716
708

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Profiles of Scaled Target-Factor Weighting Factors from Nonlinear-
Least-Squares Fitting of Selected Reference Spectra to Primal Spectra and
Profile of Principle Residue Weighting Factor from Eigenanalysis of Residues



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Profiles of Phase Factors for Selected Reference
Spectra Obtained from Fitting to Primal Spectra

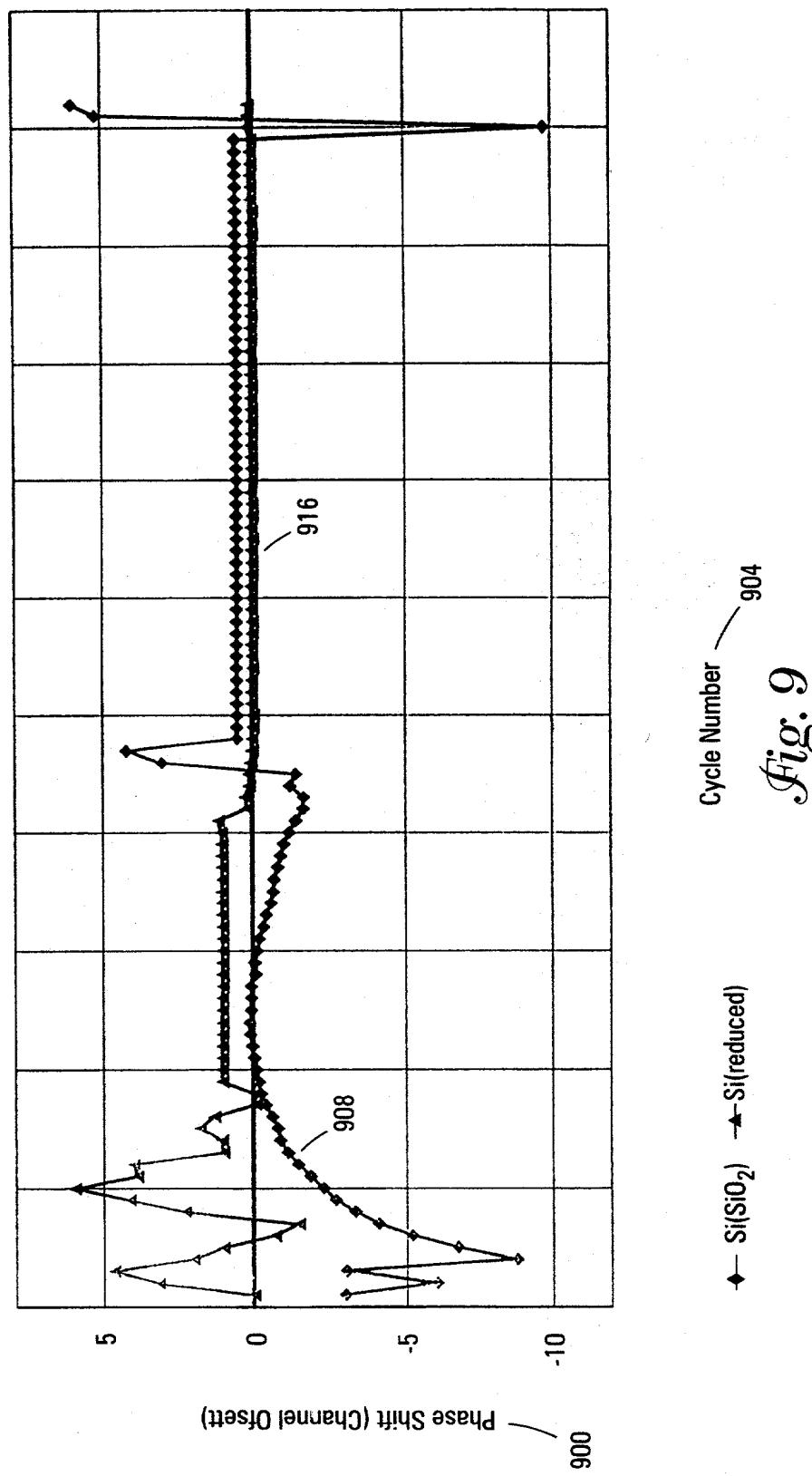


Fig. 9

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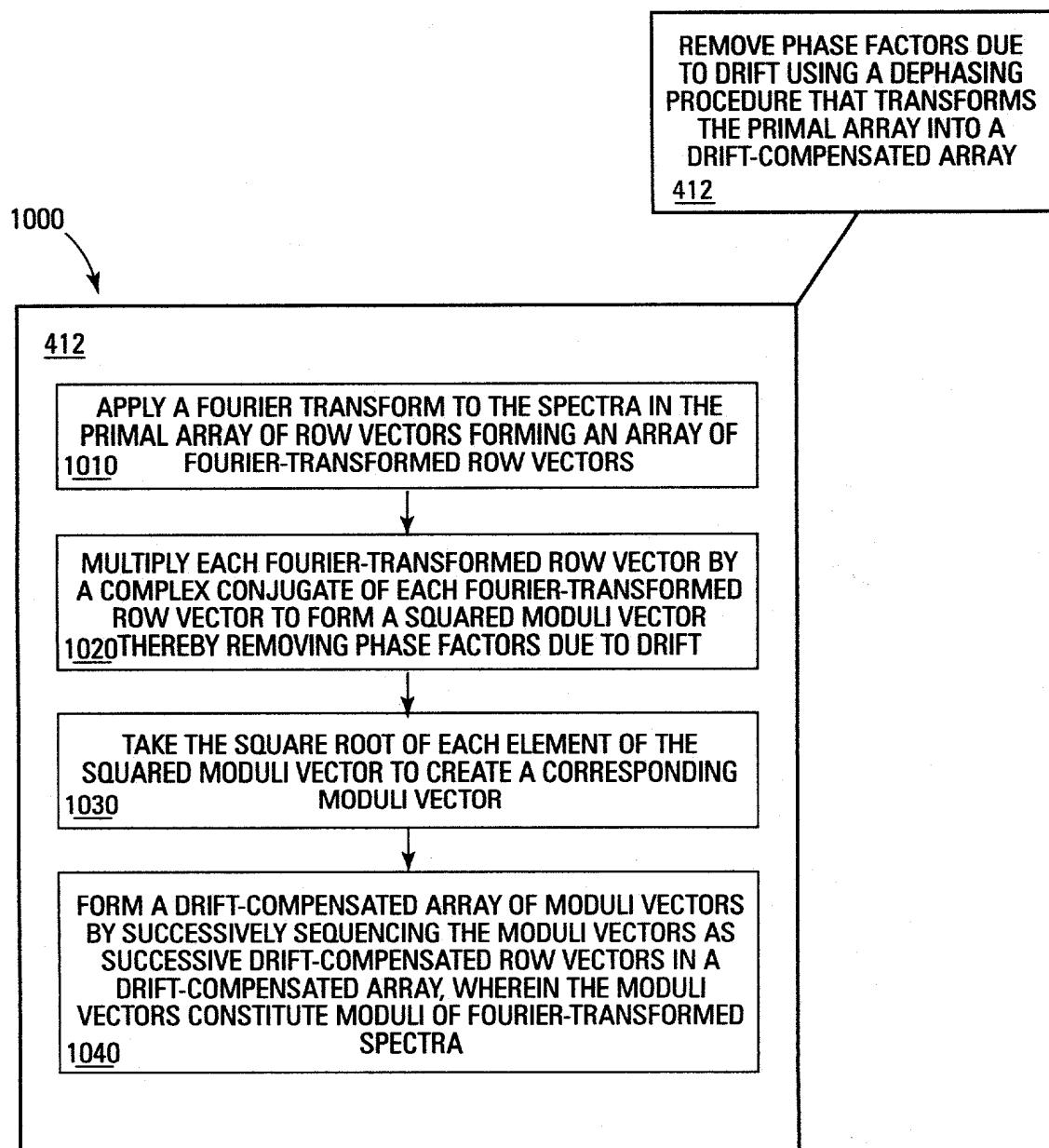


Fig. 10

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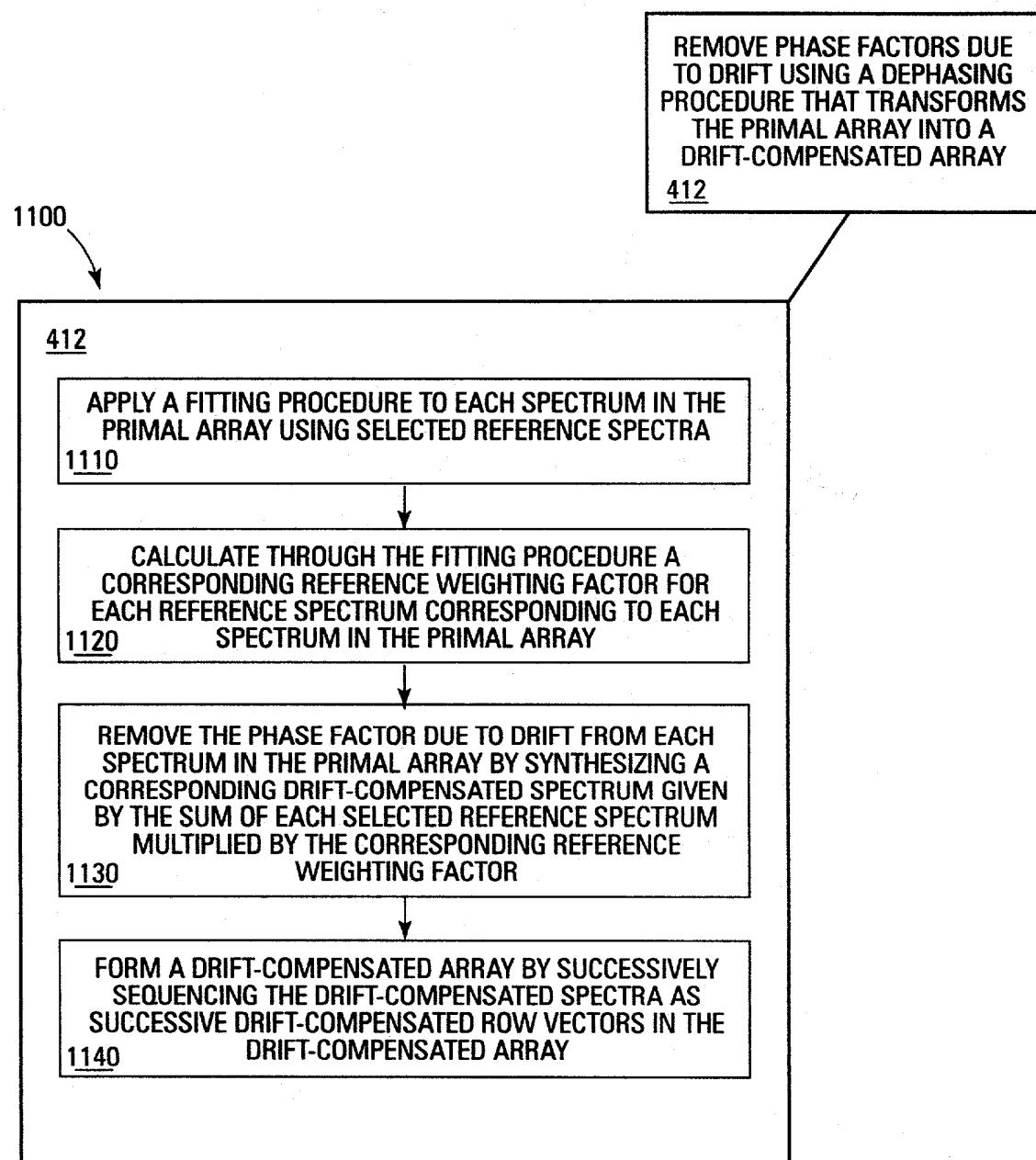


Fig. 11

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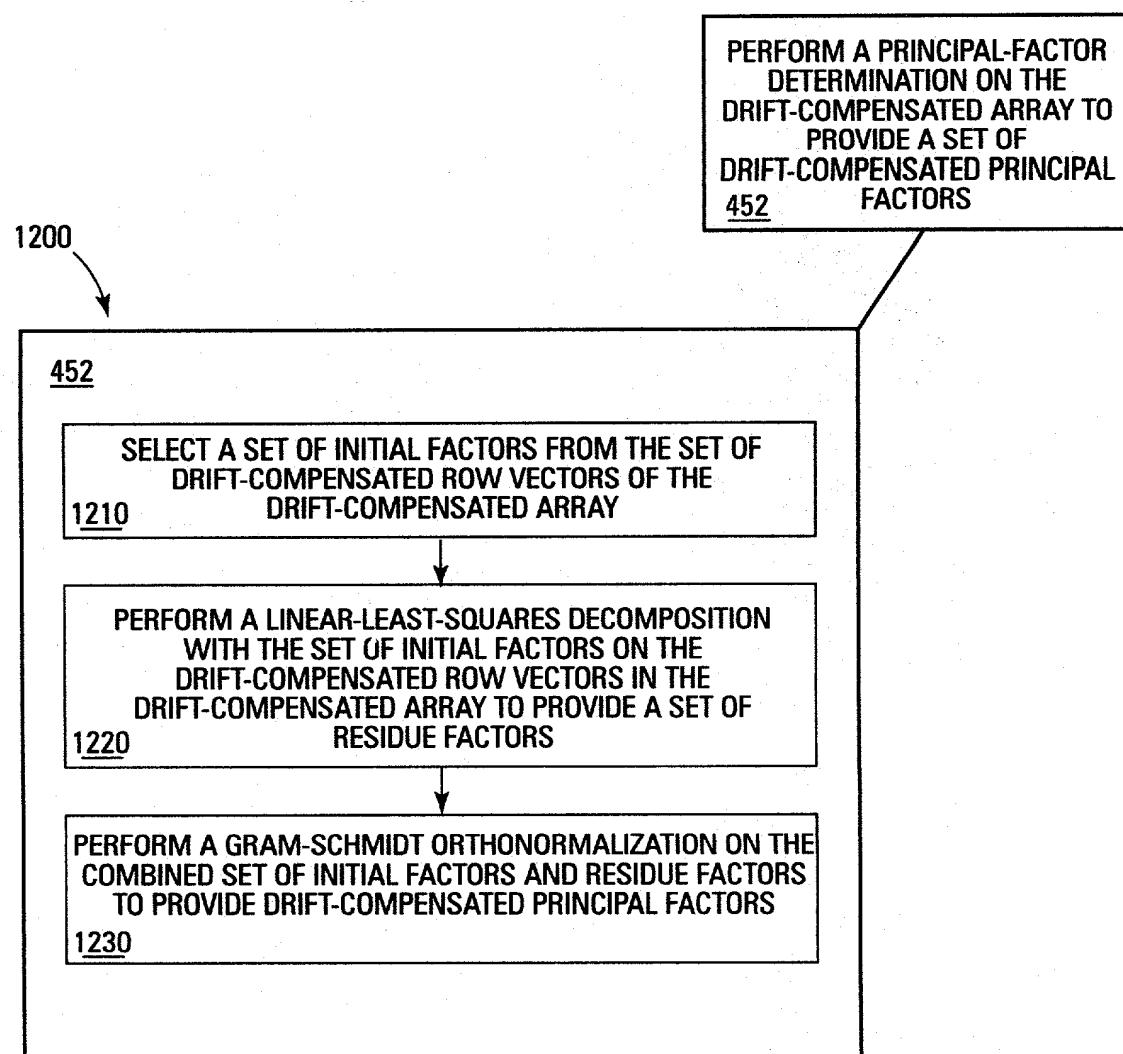


Fig. 12

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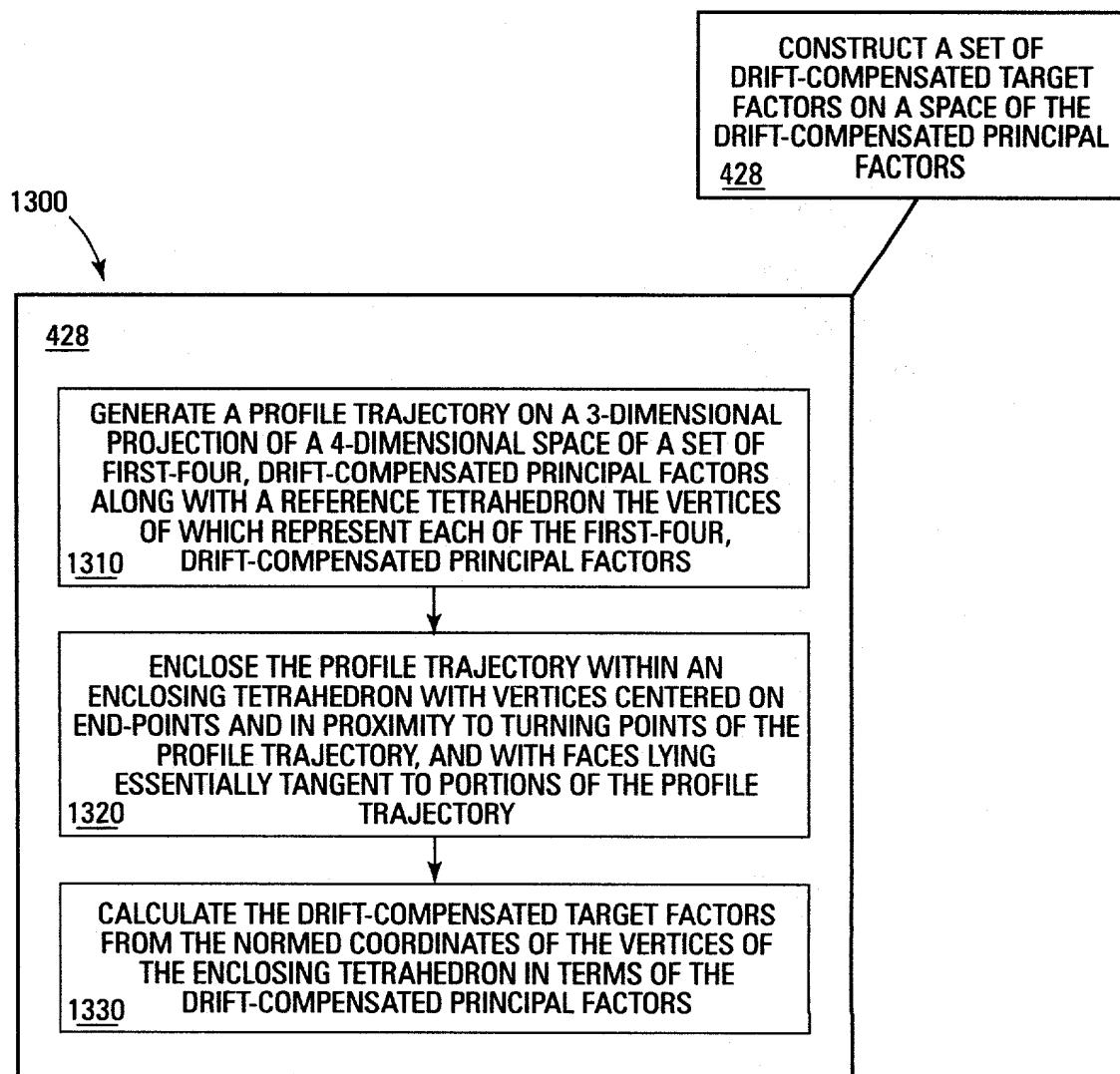
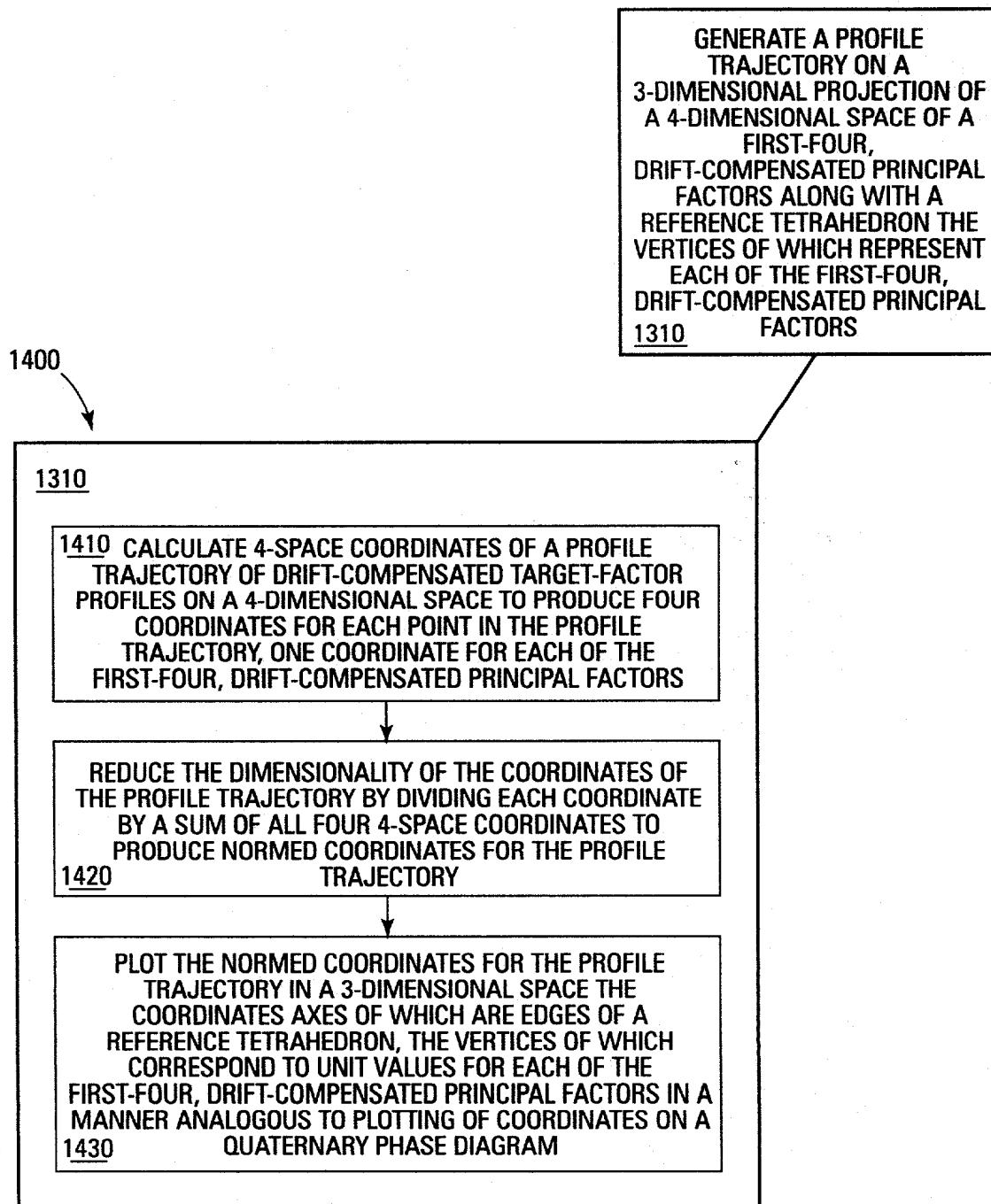


Fig. 13

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY
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*Fig. 14*

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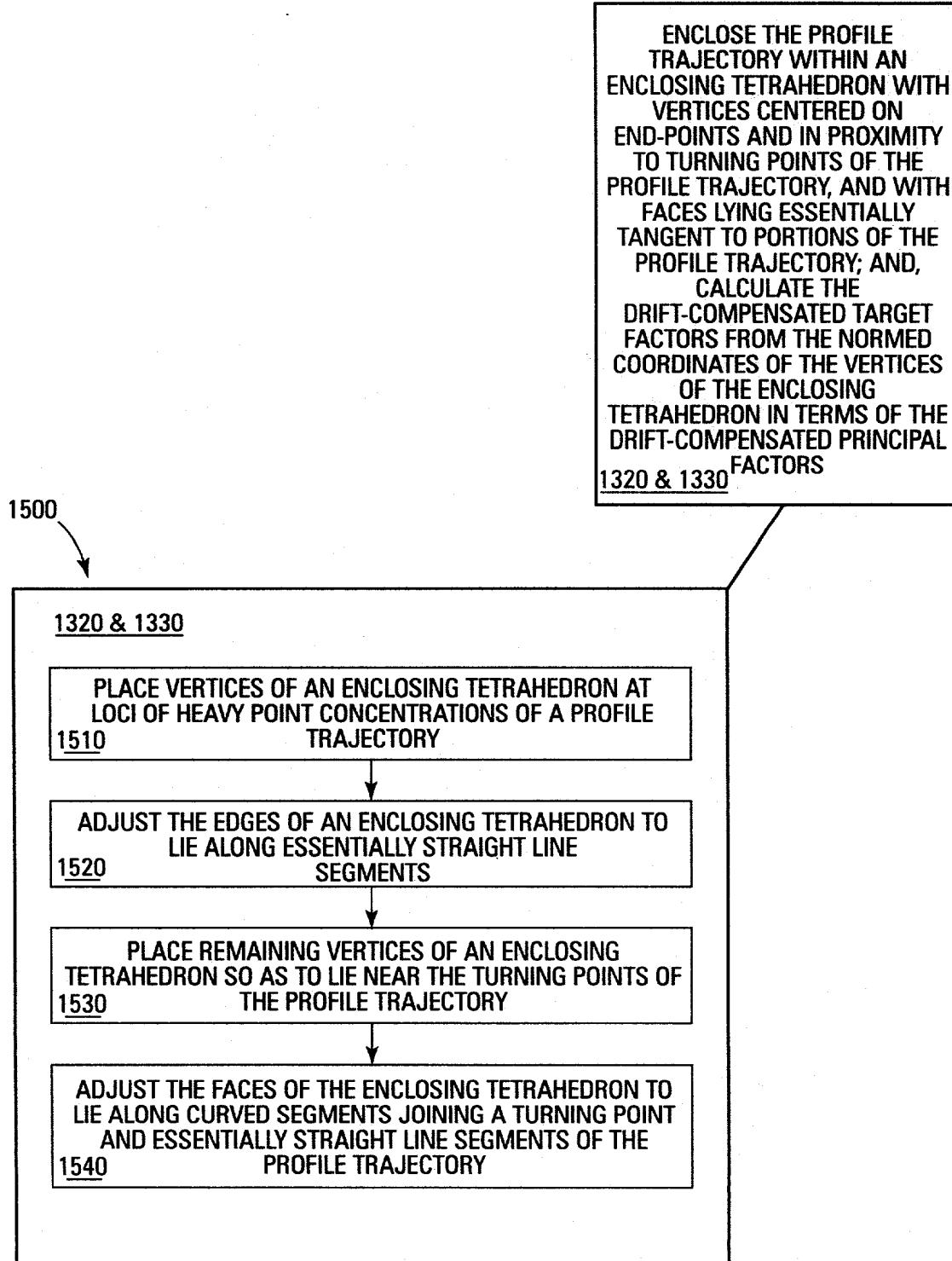


Fig. 15

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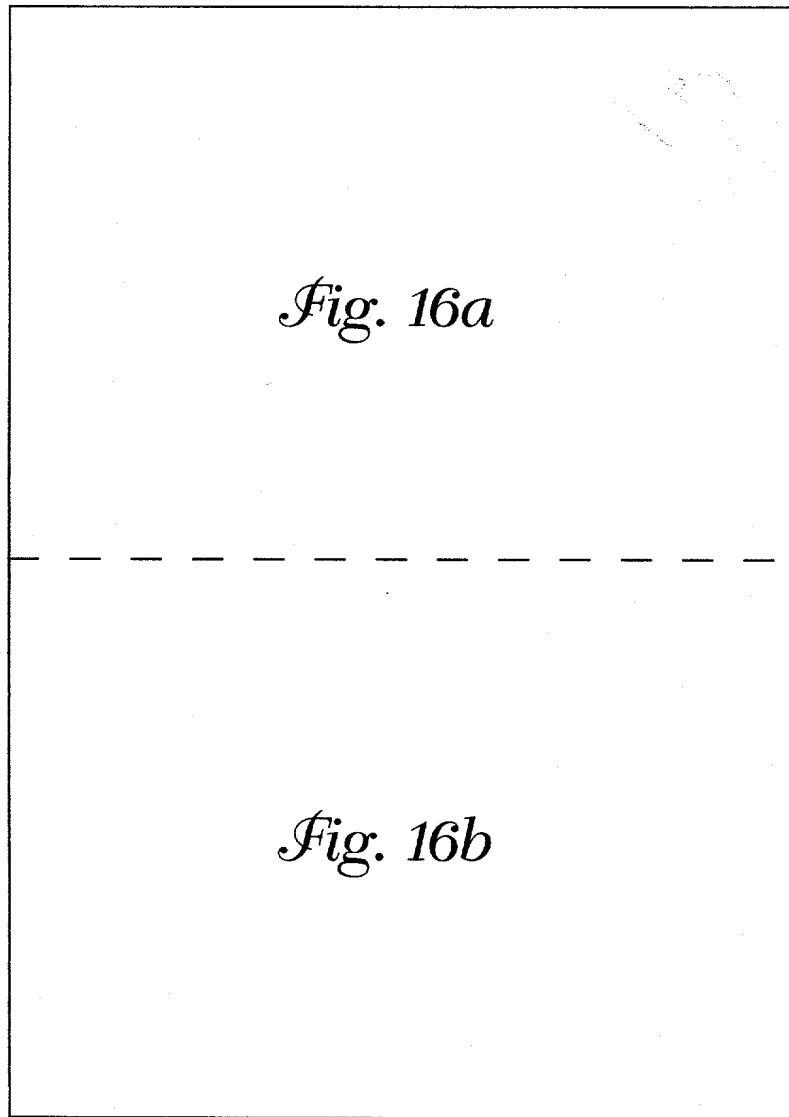
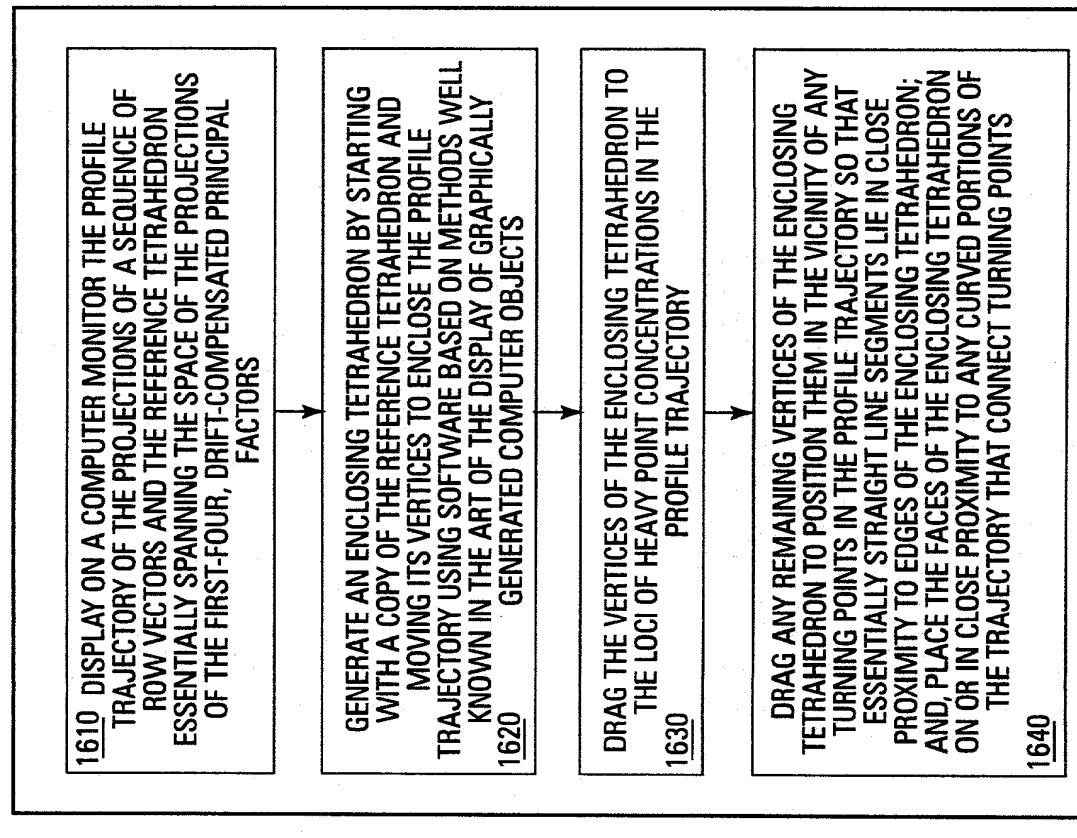


Fig. 16

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Fig. 16a



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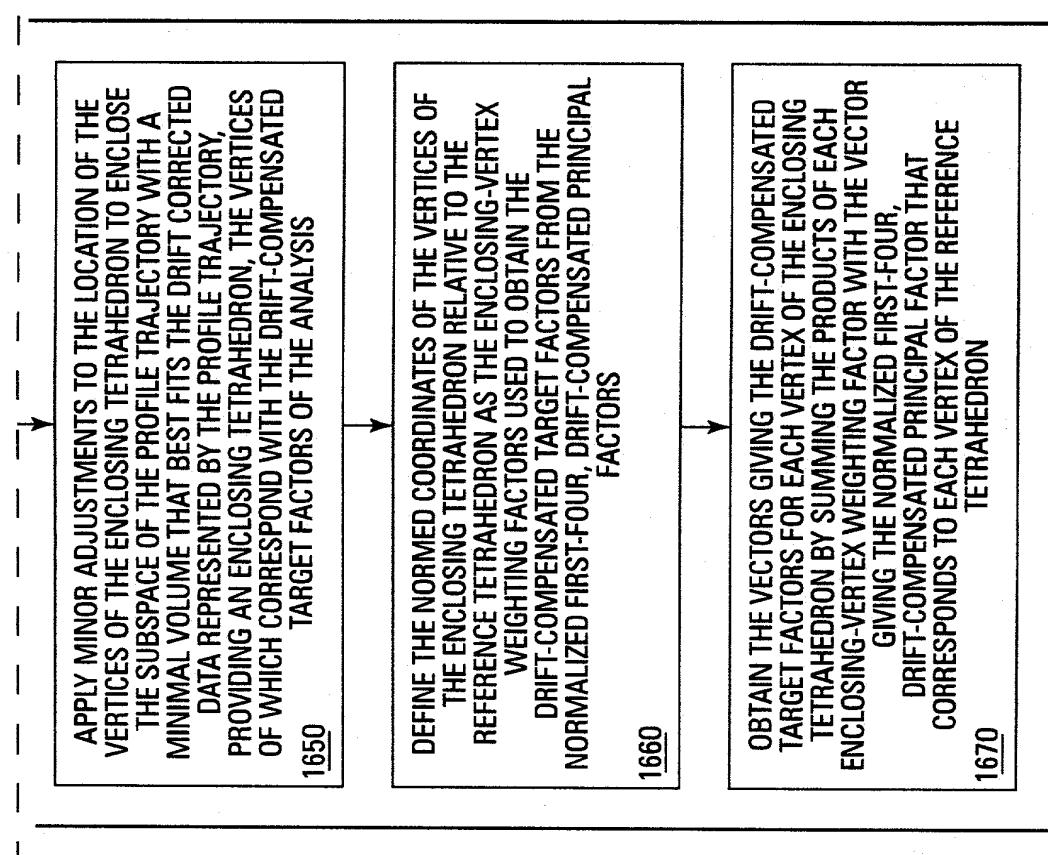
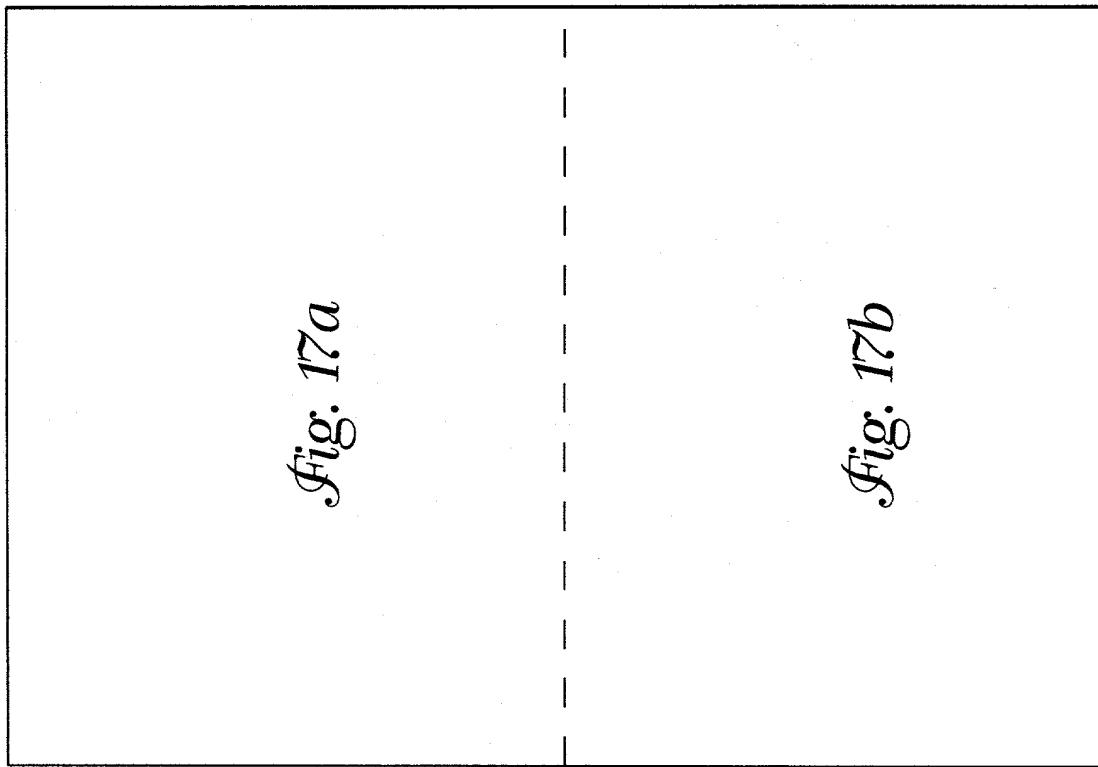


Fig. 16b

METHOD FOR REMOVING THE EFFECTS OF CHARGING FROM AUGER ELECTRON SPECTROSCOPY
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Fig. 17



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Fig. 17a

OUTPUT ANALYTICAL RESULTS
SELECTED FROM THE GROUP
CONSISTING OF A SET OF
DRIFT-COMPENSATED SCALED
TARGET-FACTOR PROFILES
DERIVED FROM THE SET OF
TARGET-FACTOR WEIGHTING
FACTORS, AND THE SET OF
DRIFT-COMPENSATED TARGET
FACTORS
436

436
OBTAIN THE SET OF DRIFT-COMPENSATED TARGET-FACTOR
PROFILE VALUES BY APPLYING THE SET OF
DRIFT-COMPENSATED TARGET FACTORS TO THE PROFILE
TRAJECTORY BY ASCERTAINING THE NORMED
COORDINATES OF EACH POINT ON THE PROFILE
TRAJECTORY, I.E. THE TARGET-FACTOR WEIGHTING
FACTORS, FROM THE ENCLOSED TETRAHEDRON IN A
MANNER ANALOGOUS TO FINDING COORDINATES OF A
POINT ON A QUARTERNARY PHASE DIAGRAM
1710

1720
COMPOSE A REFERENCE VECTOR BY SUMMING THE
PRODUCTS FORMED BY MULTIPLYING THE VECTORS
CORRESPONDING TO THE DRIFT-COMPENSATED TARGET
FACTORS BY THE TARGET-FACTOR WEIGHTING FACTORS,
FOR EACH POINT ON THE PROFILE TRAJECTORY

1730
SCALE THE AMPLITUDE OF THE RESULTING REFERENCE
VECTOR TO OPTIMALLY MATCH THE CORRESPONDING ROW
VECTOR COMPENSATED FOR THE EFFECTS OF DRIFT

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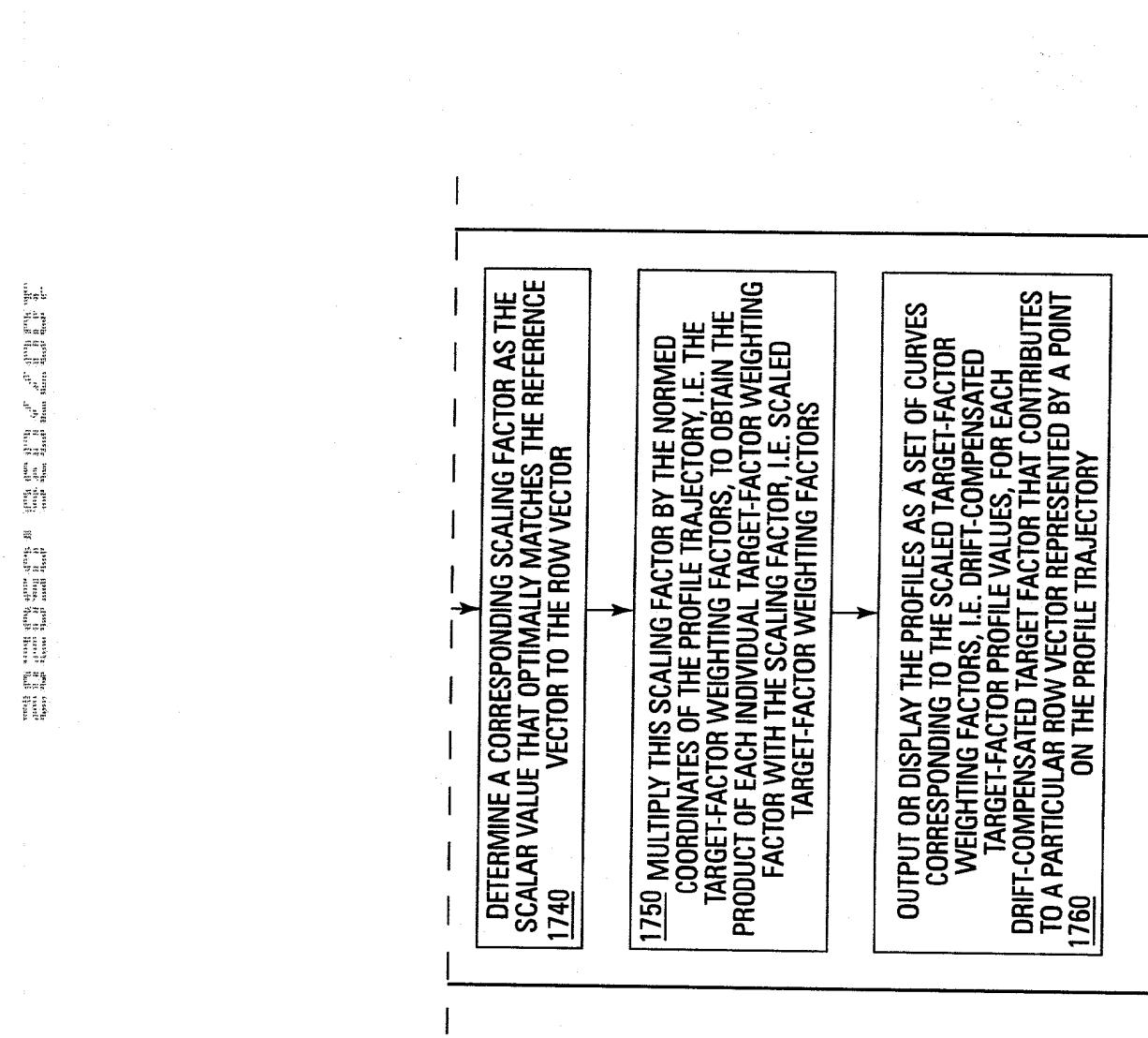


Fig. 17b

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AND ESCA COMPOSITION DEPTH PROFILES
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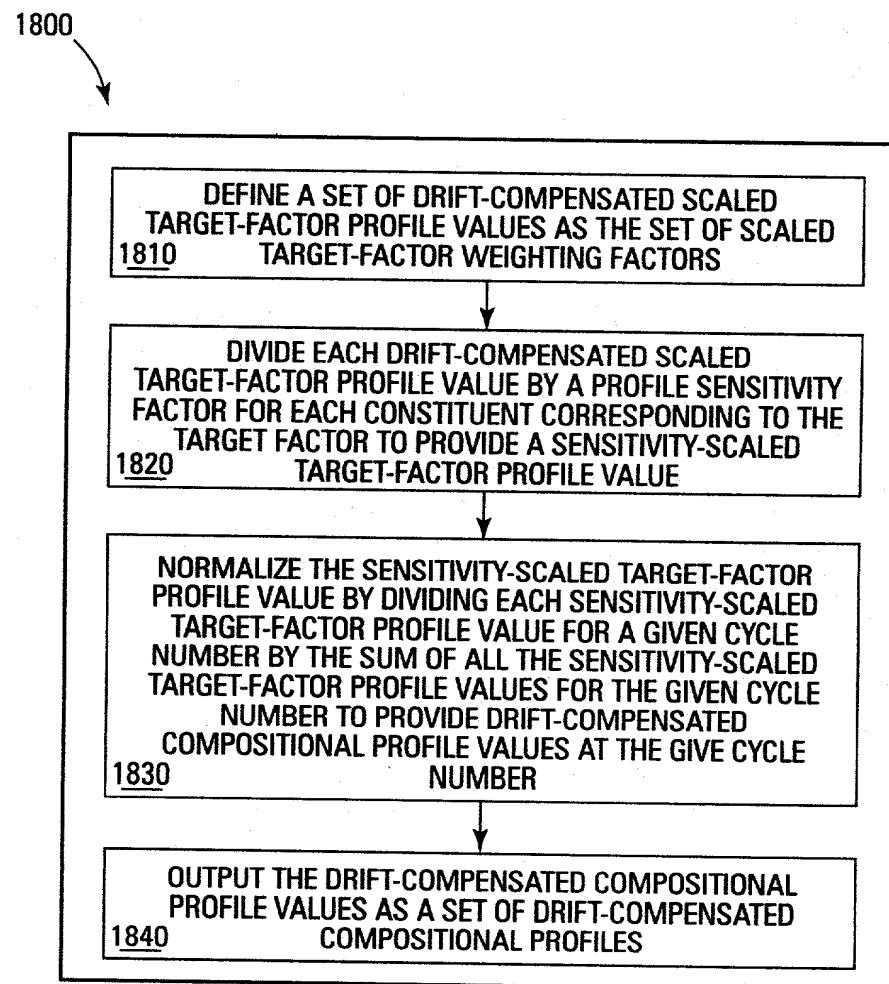


Fig. 18

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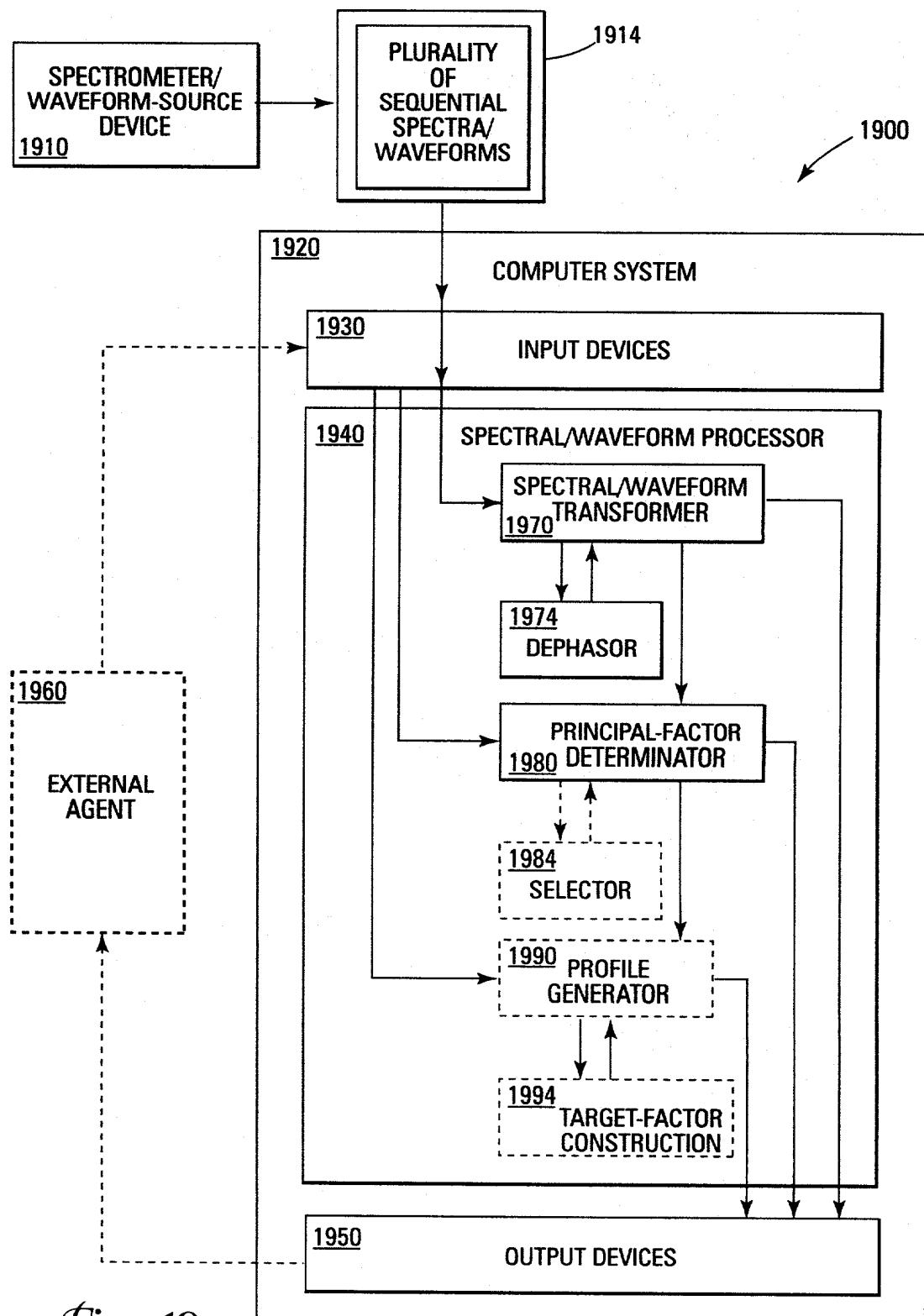


Fig. 19

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AND ESCA COMPOSITION DEPTH PROFILES
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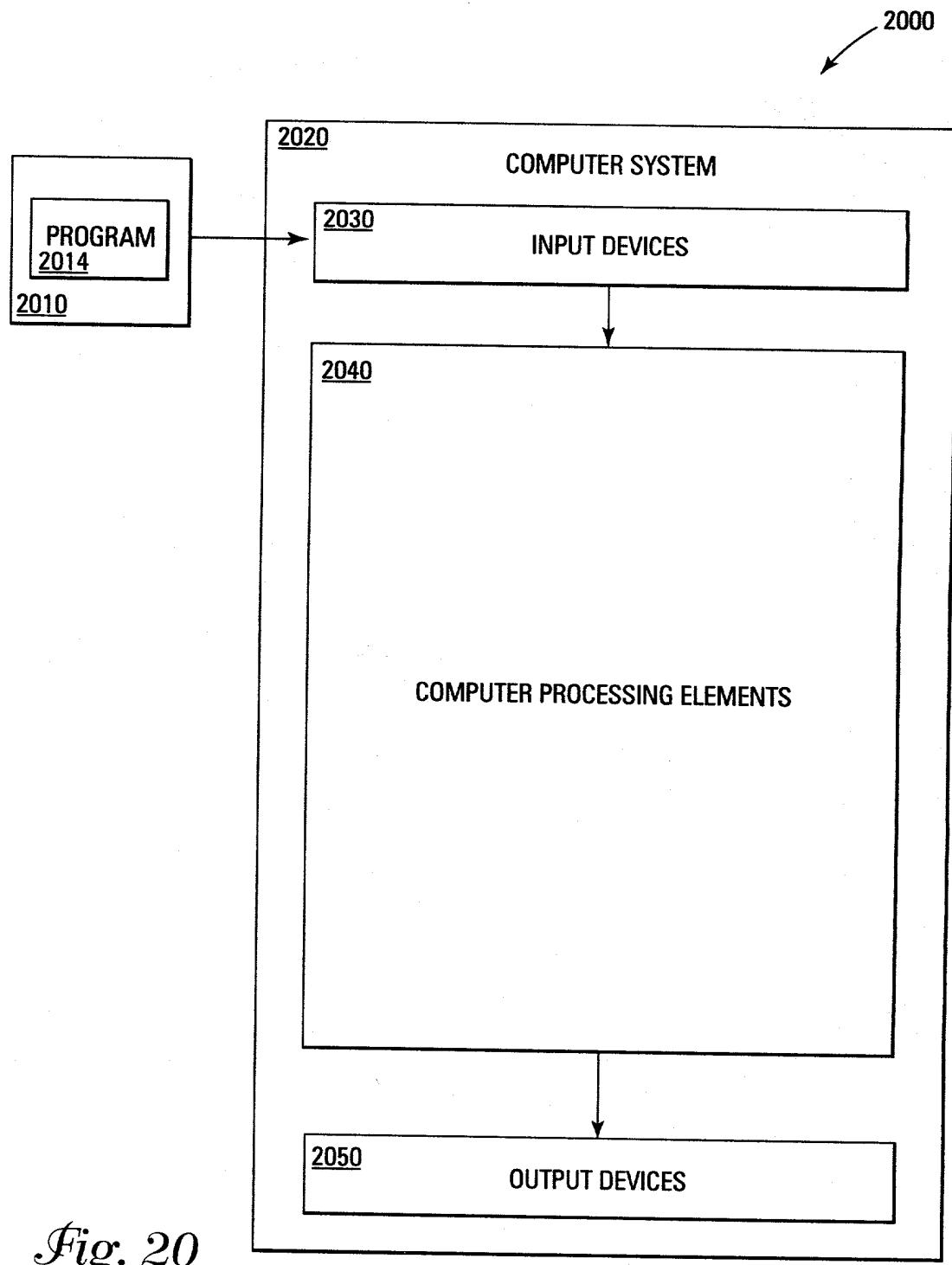


Fig. 20